



Date: October 21, 2014

Federal Communications Commission  
Office of Engineering and Technology Laboratory Division  
7435 Oakland Mills Rd.  
Columbia MD 21046

Attn: Office of Engineering and Technology

Re: HAC Attestation - FCC ID: A3LSMG530M

To whom it may concern:

Samsung Electronics hereby declares that the MIF values detailed below are based on worst case operating modes for all air interfaces for which the HAC rating is provided based on the current methodology for determining MIF values.

Reference Test report Number(s): UL Verification Services Test Report 14I19179.

<b>SPEAG test files</b>		
UID	Communication System Name	MIF (dB)
10021-DAA	GSM-FDD (TDMA, GMSK)	3.63
10011-CAA	UMTS-FDD (WCDMA)	-27.23
10170-CAB	LTE-FDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	-9.76
10176-CAB	LTE-FDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	-9.76

Sincerely,

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Hyung-Jae Lee / Engineer  
On behalf of Samsung Electronics CO. LTD.